SN54ACT16240, 74ACT16240 16-BIT BUFFERS/DRIVERS WITH 3-STATE OUTPUTS

SCAS137C - JULY 1989 - REVISED NOVEMBER 1996

- Members of the Texas Instruments Widebus™ Family
- Inputs Are TTL-Voltage Compatible
- 3-State Outputs Drive Bus Lines or Buffer Memory Address Registers
- Flow-Through Architecture Optimizes PCB Layout
- Distributed V_{CC} and GND Pin Configuration Minimizes High-Speed Switching Noise
- EPIC ™ (Enhanced-Performance Implanted CMOS) 1-µm Process
- 500-mA Typical Latch-Up Immunity at 125°C
- Package Options Include Plastic 300-mil Shrink Small-Outline (DL) Packages Using 25-mil Center-to-Center Pin Spacings and 380-mil Fine-Pitch Ceramic Flat (WD) Packages Using 25-mil Center-to-Center Spacings

description

The SN54ACT16240 and 74ACT16240 are 16-bit buffers or line drivers designed specifically to improve both the performance and density of 3-state memory address drivers, clock drivers, and bus-oriented receivers and transmitters. The devices can be used as four 4-bit buffers, two 8-bit buffers, or one 16-bit buffer. These devices provide inverting outputs and symmetrical active-low output-enable (\overline{OE}) inputs.

SN54ACT16240 . . . WD PACKAGE 74ACT16240 . . . DL PACKAGE (TOP VIEW)

1 <u>0E</u> [48	2 <u>0E</u>
1Y1 [47] 1A1
1Y2 [3	46] 1A2
GND [4	45] GND
1Y3 [5	44] 1A3
1Y4 [6	43] 1A4
V _{CC} [7	42] v _{cc}
_	8	41] 2A1
2Y2 [9	40	2A2
GND [10] GND
2Y3 [2A3
2Y4 [12	37	2A4
3Y1 [13	36	3A1
3Y2 [14	35] 3A2
GND	15] GND
3Y3		33	3A3
1 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1	17	32	
V _{CC}	18	31] v _{cc}
	19		4A1
4Y2 [29	4A2
GND [28	GND
4Y3 [27	4A3
<u>4Y4</u> [26	4 <u>A4</u>
4 0E [24	25	3 <u>OE</u>

The 74ACT16240 is packaged in TI's shrink small-outline package, which provides twice the I/O pin count and functionality of standard small-outline packages in the same printed-circuit-board area.

The SN54ACT16240 is characterized for operation over the full military temperature range of –55°C to 125°C. The 74ACT16240 is characterized for operation from –40°C to 85°C.

FUNCTION TABLE (each section)

INP	JTS	OUTPUT
OE	Α	Υ
L	Н	L
L	L	Н
н	X	Z



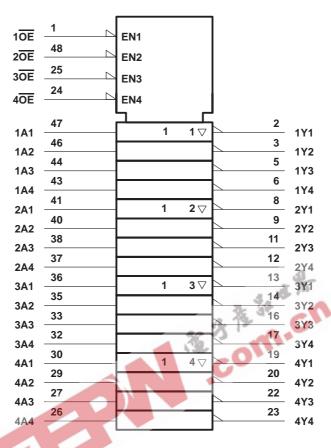
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logic symbol[†]

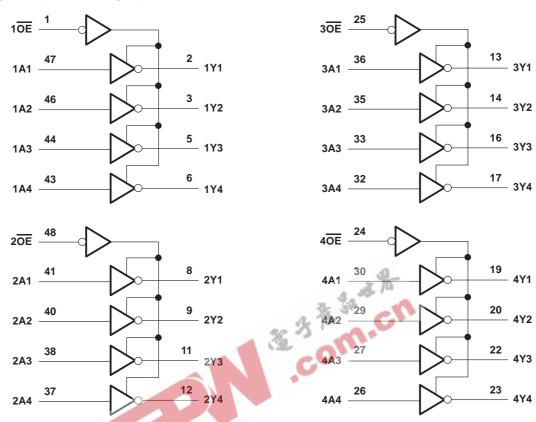


[†] This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.



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logic diagram (positive logic)



absolute maximum ratings over operating free-air temperature range (unless otherwise noted)†

Supply voltage range, V _{CC}	
Output voltage range, V _O (see Note 1)0	
Input clamp current, I_{IK} ($V_I < 0$ or $V_I > V_{CC}$)	±20 mA
Output clamp current, I_{OK} ($V_O < 0$ or $V_O > V_{CC}$)	±50 mA
Continuous output current, I_O ($V_O = 0$ to V_{CC})	±50 mA
Continuous current through V _{CC} or GND	±400 mA
Maximum package power dissipation at T _A = 55°C (in still air) (see Note 2): DL package	1.2 W
Storage temperature range, T _{stg}	–65°C to 150°C

[†] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.



NOTES: 1. The input and output voltage ratings may be exceeded if the input and output current ratings are observed.

^{2.} The maximum package power dissipation is calculated using a junction temperature of 150°C and a board trace length of 750 mils.

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recommended operating conditions (see Note 3)

		SN54ACT16240		74ACT16240			UNIT	
		MIN	NOM	MAX	MIN	NOM	MAX	UNIT
Vcc	Supply voltage	4.5	5	5.5	4.5	5	5.5	V
VIH	High-level input voltage	2		7	2			V
VIL	Low-level input voltage		Š	0.8			0.8	V
٧ _I	Input voltage	0	200	Vcc	0		VCC	V
VO	Output voltage	0	7.	VCC	0		VCC	V
loh	High-level output current		3	-24			-24	mA
loL	Low-level output current	20,00	7	24			24	mA
Δt/Δν	Input transition rise or fall rate	0		10	0		10	ns/V
TA	Operating free-air temperature	-55		125	-40		85	°C

NOTE 3: Unused inputs must be held high or low to prevent them from floating.

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS	V	ΤΔ	√ = 25°C	SN54ACT16240		74ACT16240		UNIT
PARAMETER	TEST CONDITIONS	VCC	MIN	TYP MAX	MIN	MAX	MIN	MAX	UNII
	I _{OH} = -50 μA	4.5 V	4.4	12 13	4.4		4.4		
	ΙΟΗ = 30 μΛ	5.5 V	5.4		5.4		5.4		
Voн	Ιου = -24 mΔ	4.5 V	3 .94	~O.	3.7		3.8		V
VOH	I _{OH} = -24 mA	5.5 V	4.94		4.7		4.8		V
	I _{OH} = -50 mA [†]	5.5 V			3.85				
	I _{OH} = -75 mA [†]	5.5 V					3.85		
	I _{OL} = 50 μA	4.5 V		0.1		0.1		0.1	V
		5.5 V		0.1	4	0.1		0.1	
V _{OL}	I _{OL} = 24 mA	4.5 V		0.36	Q	0.5		0.44	
VOL.		5.5 V		0.36	(5)	0.5		0.44	
	I _{OL} = 50 mA [†]	5.5 V			$g_{Q_{\zeta}}$	1.65			
	I _{OL} = 75 mA [†]	5.5 V			946			1.65	
lį	$V_I = V_{CC}$ or GND	5.5 V		±0.1		±1		±1	μΑ
loz	$V_O = V_{CC}$ or GND	5.5 V		±0.5		±10		±5	μΑ
lcc	$V_I = V_{CC}$ or GND, $I_O = 0$	5.5 V		8		160		80	μΑ
∆l _{CC} ‡	One input at 3.4 V, Other inputs at VCC or GND	5.5 V		0.9		1		1	mA
C _i	V _I = V _{CC} or GND	5.5 V		4.5					pF
Co	$V_O = V_{CC}$ or GND	5 V		12					pF

[†] Not more than one output should be tested at a time, and the duration of the test should not exceed 10 ms.

[‡] This is the increase in supply current for each input that is at one of the specified TTL voltage levels rather than 0 V or VCC.

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S1

VOLTAGE WAVEFORMS

switching characteristics over recommended operating free-air temperature range, $V_{CC} = 5 \text{ V} \pm 0.5 \text{ V}$ (unless otherwise noted) (see Figure 1)

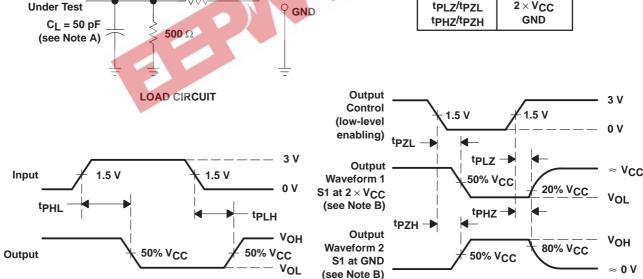
PARAMETER	FROM	то	T,	T _A = 25°C		SN54ACT16240		74ACT16240		UNIT
FARAMETER	(INPUT)	(OUTPUT)	MIN	TYP	MAX	MIN	MAX	MIN	MAX	UNIT
^t PLH	Δ.	Y	2.3	5	7.7	2	9.5	2.3	8.5	200
^t PHL	A		4.1	6.7	9.2	3	11.5	4.1	10.2	ns
^t PZH	ŌĒ	Y	2.6	5.6	8.5	2	10.1	2.6	9.4	no
^t PZL	OE		'	3.3	6.7	10.2	2.5	12.2	3.3	11.4
^t PHZ		= v	5.9	8.3	11	4.5	12.7	5.9	12	no
t _{PLZ}	ŌĒ	·	5.1	7.4	9.9	4	12	5.1	10.7	ns

operating characteristics, $V_{CC} = 5 \text{ V}$, $T_A = 25^{\circ}\text{C}$

PARAMETER		TEST CON	TYP	UNIT	
C _{pd} Power dissipation capacitance per driver	Outputs enabled	C 50 pE	f = 1 MHz	38	25
	rower dissipation capacitance per driver	Outputs disabled	$C_L = 50 \text{ pF},$	1 = 1 1011112	9

PARAMETER MEASUREMENT INFORMATION

TEST 500 Ω tPLH/tPHL Open From Output



NOTES: A. C_L includes probe and jig capacitance.

VOLTAGE WAVEFORMS

- B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
- C. All input pulses are supplied by generators having the following characteristics: PRR \leq 1 MHz, $Z_{O} = 50 \Omega$, $t_{r} = 3 \text{ ns}$, $t_{f} = 3 \text{ ns}$.
- D. The outputs are measured one at a time with one input transition per measurement.

Figure 1. Load Circuit and Voltage Waveforms



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